**FOCUSED ION BEAM (FIB) STRUCTURING / ANALYSIS REQUEST FORM**

**TECHNICAL INFORMATION**

**SERVICE REQUEST:**

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| **☐ TEM Sample Preparation** **☐ Slicing/Imaging**☐ Scanning Electron Imaging (SE-I) ☐ Back-scattered Electron Imaging (BSE-I)☐ EDX Spectral Analysis ☐ EDX Mapping Elements expected to be detected in the analysis:   |

**PURPOSE OF THE REQUEST** : (please describe the scientific aim of your project, what is the problem you want to solve with FIB; ***maximum 500 words***

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**PRELIMINARY INVESTIGATIONS DONE by the requester (NOT citations from the literature):**

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**EXPECTED RESULTS:** (please explain the results you want to obtain, what are the possible answers you expect to get by FIB analysis; ***maximum 500 words****)*

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[ ]  please attach significiant publications relevant to the subject of research

**SPECIAL SAMPLE PREPERATION** (Please state if you need metal coating (sputtering) or mechanical sample preparation (e.g. cutting, cropping) requirements. If yes, please describe.

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**SPECIMEN IDENTIFICATION**

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| **Number of samples to be analyzed** |  |
| **Sample ID and composition** | 1- |
| 2- |
| 3- |
| **What is the size of the region of interest in the sample (specify unit)** |  |
| **Type of specimen** | [ ]  Inorganic [ ]  Organic |
| **Sample Type** | [ ]  Powder [ ]  Thin Film [ ]  Bulk[ ]  Composite[ ]  magnetic [ ]  wet [ ]  toxic  |
| **I would like to have unused specimen returned****I would like to have analyzed specimen returned** |  [ ]  Yes [ ]  No [ ]  Yes [ ]  No |
| **Are there any safety precautions to consider with these specimen, to human health or to the equipment (if the answer is yes, please explain below, attach MSDS forms and write the exposure limits)** |  [ ]  Yes (please explain below) [ ]  No  [ ]  MSDS attached Exposure limits:……..  |

Possible environmental risk or safety issues:

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**IMPORTANT INFORMATION**

1. The specimens may be in different forms: bulk, thin film, powder or composite. Liquid samples are not accepted/investigated.
2. A detailed documentation with specimen numbering has to be written in the request form. Information given has to match with the labels on the specimens.
3. **Area of the specimen** must not exceed **4 cm2** and the **thickness/height** of the specimen must not exceed **1 cm**. **The depth of the region** to be analyzed should be at the **"micrometer"** level.
4. Analysis duration ranges **between 2 hrs (minimum) to 6** or more hours **for one sample** depending on the techniques that will be used at the FIB.
5. Digital data obtained after the analysis is **only** shared with the Gmail addresses written at the beginning of this form via Google Drive.
6. When disseminating, in publications or conferences, the results obtained in the analysis performed in SUNUM, the requesters are required to acknowledge the SUNUM support with a formal sentence: *“****The electron microscopy analysis leading to these results was performed at the Sabanci University Nanotechnology Research and Application Center - SUNUM” .***
7. Some special analysis may require adding the name of the scientists performing the analysis in the co-authorship for any publications using the results of the electron microscopy analysis performed in SUNUM***.***
8. SUNUM is not responsible for any inconvenience that may be caused due to inappropriate sample, incomplete and incorrect information. SUNUM has right to reject the specimen if the specimen is inappropriate, or if the form is not filled properly.